

IEEE 1687 compliant ecosystem for embedded instrumentation access and in-field health monitoring

Tšertov, Anton; Jutman, Artur; Shibin, Konstantin; **Devadze, Sergei** IEEE AUTOTESTCON 2018 : National Harbor, September 17-20, 2018 : proceedings 2018 / 9 p.: ill <https://doi.org/10.1109/AUTEST.2018.8532559>

IEEE P1687 IJTAG demonstrator on FPGA

Shibin, Konstantin; Aleksejev, Igor; Jutman, Artur; Devadze, Sergei DATE 2012 University Booth : Design Automation and Test in Europe : Dresden, Germany, March 12-16, 2012 2012 / 1 p. : ill

Invited paper: System-Wide Fault Management based on IEEE P1687 IJTAG

Jutman, Artur; Devadze, Sergei; Aleksejev, Jevgeni 6th International Workshop on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC) : 20-22 June 2011, Montpeillier, France 2011 / [4] p.: ill

Optimization of boundary scan tests using FPGA-based efficient scan architectures

Aleksejev, Igor; Devadze, Sergei; Jutman, Artur; Shibin, Konstantin Journal of electronic testing : theory and applications (JETTA) 2016 / p. 245-255 : ill <http://dx.doi.org/10.1007/s10836-016-5588-y>

Reliable health monitoring and fault management infrastructure based on embedded instrumentation and IEEE 1687

Jutman, Artur; Shibin, Konstantin; Devadze, Sergei IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 240-249 : ill <https://doi.org/10.1109/AUTEST.2016.7589605>

System-wide fault management based on IEEE P1687 IJTAG

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